

## Q8326 Optical Wavelength Meter

Measures Optical Wavelength with High Accuracy of 2 ppm and High Resolution of 0.001 nm.

- Fast sampling: Five measurements/sec.
- Frequency and deviation displays







## Wavelength Meter Using He-Ne Laser as Reference Wavelength

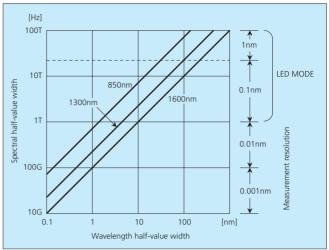
The Q8326 is an optical wavelength meter that measures an emission center wavelength with high resolution.

The Q8326 uses a He-Ne laser for the reference wavelength and uses the Michelson interference method to enable high accuracy measurement. This wavelength meter achieves fast sampling (five per second) which is optimum for oscillation wavelength adjustment of LD for DWDM. With the deviation display function, wavelength fluctuations can also be measured with high resolution and accuracy.

## Applications

- Optimum for LD wavelength adjustment for DWDM due to fast sampling measurement.
- Can be used as a wavelength standard for spectroscope calibration due to high accuracy.
- Can be automated to measure the LD wavelength temperature characteristics and wavelength current characteristics.

#### Half-value width and measurement resolution





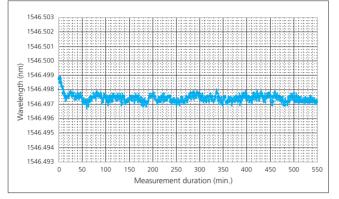
## **High Resolution**

The Michelson interference method allows high resolution measurements of up to 0.001 nm/100 MHz.

## **High Accuracy Measurements**

Use of a He-Ne laser for the reference wavelength enables high accuracy measurements of up to 2 ppm. In addition, since the He-Ne laser oscillates with high stability, a 2 ppm measurement accuracy is guaranteed over a long time period without recalibration.

## Sample of Light Source Stability



## Wide Bandwidth

The measurement range covers short wavelengths of 480 to 1000 nm and long wavelengths of 1000 to 1650 nm and is selectable via a single switch operation.

## **High-speed Sampling**

The Q8326 can measure wavelengths at a sampling speed of five per second so that wavelength fluctuations caused by temperature variations can be captured precisely.

## **Frequency and Deviation Displays**

The Q8326 can not only display the wavelength but can also be switched to display the frequency of the beam under measurement, which is convenient for adjusting the oscillation wavelength to the ITU-T grid. Since the deviation is displayed using the keyed entry as the reference, wavelength fluctuations of the LD caused by temperature variations can be viewed with high resolution and high precision.

## **GPIB Provided as Standard**

Standard provision of GPIB allows the Q8326 to be used as a component for an automated measuring system utilizing fast sampling.



#### **Performance Parameters**

Wavelength

Wavelength	480 to 1650 nm (181 to 625 THz)
Measurement range: Accuracy:	±2 ppm±1 count*1*2
Display resolution:	1 nm to 0.0001 nm* <sup>3</sup>
Power Level	
Sensitivity:	-15 dBm (480 to 600 nm)
	-25 dBm (600 to 1650 nm) -30 dBm (1200 to 1600 nm)
Max. input level:	+10 dBm
Measurement Duration	
Duration:	0.2 seconds
Functions	
Average:	Displays moving average of 10 measurement
Deviation measurement:	Displays deviation from the reference
	measurement value.
Optical Input	
Applicable fiber:	50/125 µm GI fiber
	9.5/125 μm SM fiber (recommended)
Connector (user replaceable):	FC (standard), ST, SC (separately available)
I/O Interface	
GPIB:	IEEE488-1978
Analog output:	Analog output with lower three digits displaye 0 to +1 V
General Specifications	
Operating environment:	Temperature; +10 to +40°C
	Relative humidity; 85% or less
	(no condensation)
Accuracy guaranteed	a= 40°2
temperature range:	+25 ±10°C
Storage environment:	Temperature; -10 to +50°C
	Relative humidity; 90% or less (no condensation)
Power supply:	100 to 240 VAC, 50/60 Hz, 60 VA or less
Dimensions:	Approx. 300 (W) x 132 (H) x 450 (D) mm
	10.5 kg or less

#### Separately Available Accessories

A08161
A08162
A08163
OCS-F2SFW-2 (GI 50/125 µm, 2 m)
OCS-F2SPS-2 (SM 10/125 µm, 2 m)
-
A02250
A02450

\*1) In case of single mode laser of beam width 10 GHz or less

In other cases, ±Full width [nm] at half maximum x 1/10 [nm] ±2 ppm ±1 count \*2) ±5 ppm for 600 nm or less

\*3) 0.0001 nm display is available for average measurement only.

Please be sure to read the product manual thoroughly before using the products. Specifications may change without notification.

# **ADVANTEST**

#### ADVANTEST CORPORATION

Shinjuku-NS building, 4-1 Nishi-Shinjuku 2-chome Shinjuku-ku, Tokyo 163-0880, Japan Tel: +81-3-3342-7500 Fax: +81-3-5322-7270 http://www.advantest.co.jp Advantest Korea Co., Ltd. 16F, MIRAEWASARAM Bldg., 942-1, Daechi-Dong, Kangnam-ku, #135-280, Seoul, Korea Tel: +82-2-3452-7157 Fax: +82-2-3452-0370

## China:

Korea:

Advantest (Suzhou) Co., Ltd. Shanghai Branch Office 5F, No.46 Section Factory Building, No.555 Gui Ping Road, Caohejing, Hi-Tech Area, Shanghai, China 200233 Tel: +86-21-6485-2725 Fax: +86-21-6485-2726

## Beijing Branch Office

Room 517, Beijing Fortune Bldg., 5 Dong San Huan Bei-Lu, Chan Yang District, Beijing, China 100004 Tel: +86-10-6590-8170 Fax: +86-10-6590-8175

## Taiwan:

Advantest Taiwan Inc. No.1 Alley 17, Lane 62, Chung-Ho Street, Chu-Pei City, Hsin Chu Hsien, Taiwan R.O.C Tel: +886-3-5532111 Fax: +886-3-5541168

## Singapore, Malaysia, Thailand, Indonesia, Philippines, Vietnam:

**Advantest (Singapore) Pte. Ltd.** 438A Alexandra Road, #08-03/06 Alexandra Technopark Singapore 119967 Tel: +65-6274-3100 Fax: +65-6274-4055

## North America, Canada, Mexico: Advantest America Measuring Solutions, Inc. Head Office 258 Fernwood Avenue Edison, NJ 08837, U.S.A. Tel: +1-732-346-2600 Fax: +1-732-346-2610 http://www.advantest.com/ ProdServices/instr.htm

Santa Clara Office 3201 Scott Blvd., Santa Clara, CA 95054, U.S.A. Tel: +1-408-988-7700 Fax: +1-408-987-0688

#### Europe:

Rohde & Schwarz Engineering and Sales GmbH Mühldorfstraße 15 D-81671 München, Germany (P.O.B. 80 14 29 D-81614 München, Germany) Tel: +49-89-4129-13711 Fax: +49-89-4129-13723